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Pre Amended
S. Zimmerman*

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Date: June 4, 2002

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Beaman et al.

Group Art Unit: 3729

JUN 04 2002

Serial No.: 09/921,867

Examiner:

GROUP 3700

Filed: August 3, 2001

Docket No.: YOR919930028US6

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS,
TEST PROBE AND METHODS OF USE THEREOF


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Assistant Commissioner for Patents
Washington, D. C. 20231

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CFR 1.61(d) to the U.S. Patent and Trademark Office to (703) 872-9302 on June 4,
2002.
Dr. Daniel P. Morris, Esq.
Reg. No. 32,053FORTH PRELIMINARY AMENDMENT

IN THE CLAIMS

37
CFR
1.120
144
Added claims 145-195.

145. (Added) A semiconductor device comprising:

a silicon body having a plurality of contact locations;

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01 FC:103

918.00 CH

02 FC:102

1008.00 CH

Serial No. 09/921,867

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